



# 600V, 30A, Trench FS II Fast IGBT

#### **General Description**

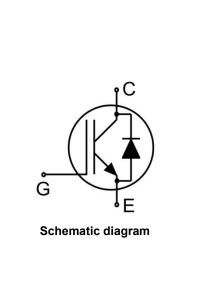
Using NCE's proprietary trench design and advanced FS (Field Stop) second generation technology, the 600V Trench FS II IGBT offers superior conduction and switching performances, and easy parallel operation;

#### Features

- Trench FSII Technology offering
- Very low V<sub>CE(sat)</sub>
- High speed switching
- Positive temperature coefficient in V<sub>CE(sat)</sub>
- Very tight parameter distribution
- High ruggedness, temperature stable behavior

#### Application

- Air Condition
- Inverters
- Motor drives



#### Package Marking and Ordering Information

Device	Device Package	Device Marking					
NCE30TD60BT	TO-247	NCE30TD60BT					



TO-247

#### Absolute Maximum Ratings (Tc=25°C unless otherwise noted)

Symbol	Parameter	arameter Value	
VCES	Collector-Emitter Voltage	600	V
V <sub>GES</sub>	Gate- Emitter Voltage	±30	V
	Collector Current	60	A
lc	Collector Current @T <sub>c</sub> = 100°C	30	A
I <sub>Cpuls</sub>	Pulsed Collector Current, t <sub>p</sub> limited by T <sub>jmax</sub>	120	A
-	turn off safe operating area,V <sub>CE</sub> =600V, T <sub>j</sub> =175°C	120	A
I <sub>F</sub>	Diode Continuous Forward Current @T <sub>c</sub> = 100°C	30	A
I <sub>FM</sub>	Diode Maximum Forward Current	120	A
Power Dissipation @ T <sub>c</sub> = 25°C		230	W
PD	Power Dissipation @T <sub>c</sub> = 100 °C	115	W
$T_{J}, T_{stg}$	Operating Junction and Storage Temperature Range	-55 to +175	°C
TL	Maximum Temperature for Soldering	260	°C
t <sub>sc</sub>	Short circuit withstand time $V_{GE}$ =15V, $V_{CC}$ 400V, Allowed number of short circuits<1000Time between short circuits: $\geq$ 1.0s, $T_j$ $\leq$ 150°C	5	us



NCE30TD60BT

#### **Thermal Characteristic**

Symbol	Parameter	Value	Units
R <sub>θJC</sub>	Thermal Resistance, Junction to case for IGBT	0.65	°C/W
R <sub>θJC</sub>	Thermal Resistance, Junction to case for Diode	0.99	°C/W
R <sub>0JA</sub>	Thermal Resistance, Junction to Ambient	40	°C/W

### **Electrical Characteristics (Tc=25°C unless otherwise noted)**

Sumb cl	Devementer	Conditions		Value			
Symbol	mbol Parameter Conditions		Min.	Тур.	Max.	Units	
Static Chara	cteristics				•	I	
V <sub>(BR)CES</sub>	Collector-Emitter Breakdown Voltage	V <sub>GE</sub> =0V	,I <sub>CE</sub> =1mA	600			V
I <sub>CES</sub>	Collector-Emitter Leakage Current	V <sub>GE</sub> =0V,	V <sub>CE</sub> =600V			40	uA
I <sub>GES(F)</sub>	Gate to Emitter Forward Leakage	V <sub>GE</sub> =+30	V,V <sub>CE</sub> =0V			200	nA
I <sub>GES(R)</sub>	Gate to Emitter Reverse Leakage	V <sub>GE</sub> =-30	V,V <sub>CE</sub> =0V			200	nA
V <sub>CE(sat)</sub>	Collector-Emitter Saturation Voltage	I <sub>C</sub> =30A V <sub>GE</sub> =15V	T <sub>j</sub> =25°C T <sub>i</sub> =175°C		1.7 1.9	1.9	V V
$V_{\text{GE(th)}}$	Gate Threshold Voltage	Ic=1mA,Vc=VGE		4.0	5.0	6.0	V
Dynamic Cha	aracteristics				•		
Cies	Input Capacitance	- V <sub>CE</sub> =25V,V <sub>GE</sub> =0V, f=1MHz			3552		pF
Coes	Output Capacitance				106		
Cres	Reverse Transfer Capacitance				67		
Qg	Total Gate Charge	V <sub>cc</sub> =480V, I <sub>c</sub> =30A, V <sub>GE</sub> =15V			132		nC
Q <sub>ge</sub>	Gate to Emitter Charge				28		
Q <sub>gc</sub>	Gate to Collector Charge				54		
I <sub>C(SC)</sub>	Short circuit collector current Max.1000 short circuits Time between short circuits: $\ge$ 1.0s	V <sub>GE</sub> =15V,V <sub>CC</sub> ≪400V, t <sub>SC</sub> ≪5us,Tj≪150°C			180		А
Switching Ch	naracteristics						
t <sub>d(ON)</sub>	Turn-on Delay Time	Vcc=400V,Ic=30A,			19		
tr	Rise Time				17		ne
$t_{\text{d}(OFF)}$	Turn-Off Delay Time				166		ns
t <sub>f</sub>	Fall Time	V <sub>GE</sub> =0/15V, R <sub>g</sub> =5Ω,			16		
$E_{on}$	Turn-On Switching Loss	Inductive Load			0.36		
$E_{off}$	Turn-Off Switching Loss				0.32		mJ
E <sub>ts</sub>	Total Switching Loss				0.68		

# Electrical Characteristics of the Diode (T<sub>c</sub>= 25°C unless otherwise specified)

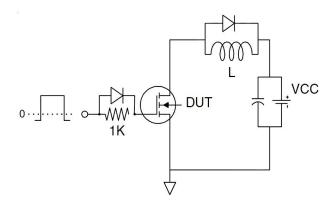
Symbol	Parameter	Conditions	Rating			Unite
		Conditions	Min.	Тур.	Max.	Units
Vfm	Diode Forward Voltage	I⊧=30A		1.75	2.40	V
Trr	Reverse Recovery Time	1 - 20 4		178		ns
I <sub>RRM</sub>	Diode Peak Reverse Recovery Current	l⊧=30A, di/dt=200A/us		4		А
Qrr	Reverse Recovery Charge	ui/ui-200A/us		0.4		uC
Pulse width t <sub>tp</sub> ≤380μs,δ≤2%						





## Test Circuit

1) Gate Charge Test Circuit



#### 2) Switch Time Test Circuit

2) Definition of switching losses

90% V<sub>GE</sub>

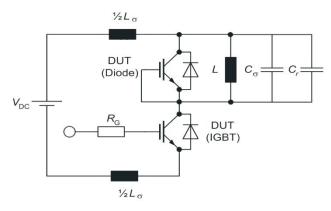
2%

V<sub>CE</sub> x I<sub>C</sub> x dt

 $V_{GE}(t)$ 

 $i_{\rm c}(t)$ 

 $V_{CE}(t)$ 



10% V<sub>GI</sub>

E<sub>on</sub> =

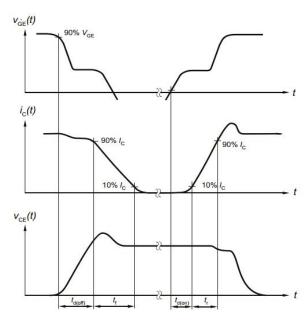
t3

VCE X I

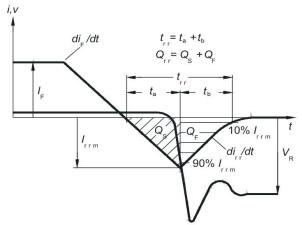
2% V<sub>CE</sub> t

### Switching characteristics

#### 1) Definition of switching times



### 3) Definition of diode switching characteristics





## **Typical Electrical and Thermal Characteristics**

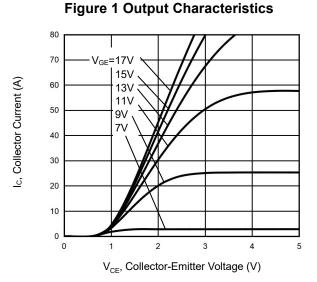
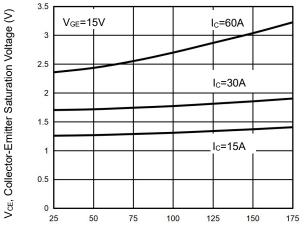
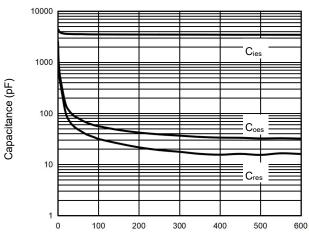


Figure 3 V<sub>CEsat</sub> vs. Case Temperature



T<sub>J</sub>, Junction Temperature (°C)

Figure 5 Capacitance Characteristics



 $V_{\text{CE}},$  Collector-Emitter Voltage (V)

80 V<sub>CE</sub>=20V 70 Ic, Collector Current (A) 60 25°C 50 150°C 40 30 20 10 0 12 15 9 3 6 V<sub>GE</sub>, Gate-Emitter Voltage (V)

# Figure 2 Transfer Characteristics

Figure 4 Saturation Voltage vs. VGE

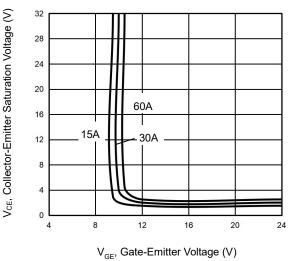
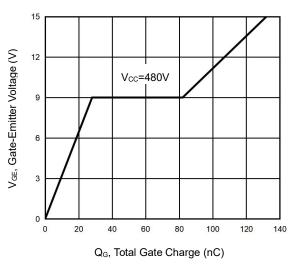


Figure 6 Gate charge waveform





# **Typical Electrical and Thermal Characteristics**

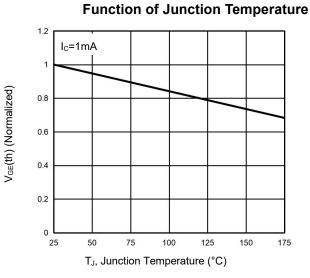
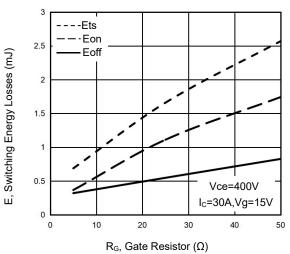
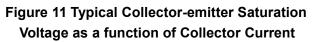


Figure 7 Gate-emitter Threshold Voltage as a

Figure 9 Typical Switching Times as a **Function of Gate Resistor** 





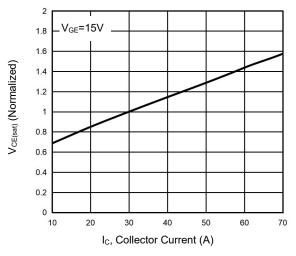


Figure 8 Power Dissipation as a Function of **Case Temperature** 

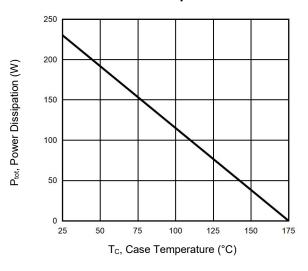


Figure 10 Typical Switching Times as a **Function of Junction Temperature** 

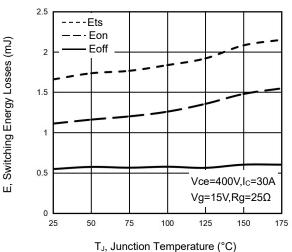
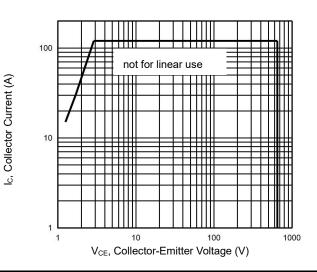
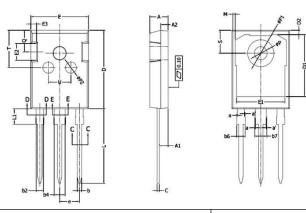


Figure 12 Forward Bias Safe Operating Area





# **TO-247-P Package Information**



Symbol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
A	4.90	5.10	0.19	0.20	
A1	2.31	2.51	0.09	0.10	
A2	1.90	2.10	0.08	0.09	
а	0.00	0.15	0.00	0.01	
a'	0.00	0.15	0.00	0.01	
b	1.16	1.26	0.05	0.06	
b2	1.96	2.06	0.08	0.09	
b4	2.96	3.06	0.12	0.13	
b6	-	2.25	-	0.09	
b7	-	3.25	-	0.13	
С	0.59	0.66	0.02	0.03	
D	20.90	21.10	0.82	0.83	
D1	16.25	16.85	0.64	0.66	
D2	1.05	1.35	0.04	0.05	
E	15.70	15.90	0.62	0.63	
E1	13.10	13.50	0.52	0.53	
E2	4.40	4.60	0.17	0.18	
E3	2.40	2.60	0.09	0.10	
е	5.436	BSC	0.214	BSC	
L	19.80	20.10	0.78	0.79	
L1	-	4.30	-	0.17	
М	0.35	0.95	0.01	0.04	
Р	3.40	3.60	0.13	0.14	
P1	7.00	7.40	0.28	0.29	
P2	2.40	2.60	0.09	0.10	
Q	5.60	6.00	0.22	0.24	
S	6.05	6.25	0.24	0.25	
Т	9.80	10.20	0.39	0.40	
U	6.00	6.40	0.24	0.25	



Pb Free Product NCE30TD60BT

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